Draft for Public Comment

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Project No. 2024/00945

Responsible committee: EPL/46 Cables, wires and waveguides, radio frequency connectors and accessories for communication and signalling

Interested committees:

Title:	BS EN IEC 61169-73 Measurement of the conductivity for metal thin films at microwave and millimeter-wave frequencies balanced-type circular disk resonator method

Please notify the secretary if you are aware of any keywords that might assist in classifying or identifying the standard or if the content of this standard
i) has any issues related to 3rd party IPR, patent or copyright
ii) affects other national standard(s)
iii) requires additional national guidance or information

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THIS DRAFT IS NOT CURRENT BEYOND 15 May 2024

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Responsible Committee Secretary: **Committee Service Centre (BSI)**
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Introduction

This draft standard is based on national and international discussions. Your comments on this draft are invited and will assist in the preparation of the consequent standard.

For international standards, comments will be reviewed by the relevant UK national committee before sending the consensus UK vote and comments to the international committee, which will then decide appropriate action. If the international standard is approved, it is usual for the text to be published as a British Standard.

For national standards, comments will be reviewed by the relevant UK national committee and the resulting standards published as a British Standard.

UK Vote

Please indicate whether you consider the UK should submit a negative (with supporting technical reasons) or positive vote on this draft. Please indicate if you are aware of any reason why this draft standard should not be published as a British Standard.

Submission of Comments

- **Annotated drafts are not acceptable and will be rejected.**
- All comments should be submitted online at **https://standardsdevelopment.bsigroup.com/**. You will need to register in order to comment.

Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx

1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex **(e.g. 3.1)**	Paragraph/Figure/ Table/Note	**Type of comment**	**Commend (justification for change) by the MB**	**Proposed change by the MB**	**Secretariat observations on each comment submitted**
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	

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46F/670/CD

COMMITTEE DRAFT (CD)

PROJECT NUMBER: **IEC 61169-73 ED1**	
DATE OF CIRCULATION: **2024-03-22**	CLOSING DATE FOR COMMENTS: **2024-06-14**
SUPERSEDES DOCUMENTS: **46F/628/NP, 46F/648/RVN**	

IEC SC 46F : RF AND MICROWAVE PASSIVE COMPONENTS	
SECRETARIAT: United States of America	SECRETARY: Mr John Morelli
OF INTEREST TO THE FOLLOWING COMMITTEES:	PROPOSED HORIZONTAL STANDARD: ☐ Other TC/SCs are requested to indicate their interest, if any, in this CD to the secretary.
FUNCTIONS CONCERNED: ☐ EMC ☐ ENVIRONMENT ☐ QUALITY ASSURANCE ☐ SAFETY	

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TITLE:

Measurement of the conductivity for metal thin films at microwave and millimeter-wave frequencies balanced-type circular disk resonator method

NOTE FROM TC/SC OFFICERS:

please see attached CD from Japanese NC

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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MEASUREMENT OF THE CONDUCTIVITY FOR METAL THIN FILMS AT MICROWAVE AND MILLIMETER-WAVE FREQUENCIES BALANCED-TYPE CIRCULAR DISK RESONATOR METHOD

FOREWORD

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International Standard IEC 63185 has been prepared by subcommittee 46F: RF and microwave passive components, of IEC technical committee 46: Cables, wires, waveguides, RF connectors, RF and microwave passive components and accessories.

The text of this standard is based on the following documents:

FDIS	Report on voting
46F/XX/FDIS	46F/XX/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

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